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Ing-Jer Huang; Tai-An Lu;

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Hunter, C.; Gaither, J.;

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Fleming, P.;

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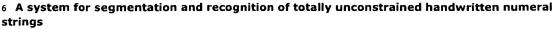


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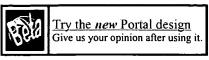
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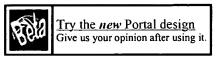
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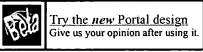


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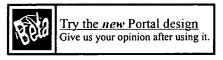
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